

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Appln. of: Werner KUHLMANN

Appln. No.: Not yet assigned

Filed: Herewith

For: SENSOR ARRANGEMENT FOR
RECORDING A RADIATION,
COMPUTER TOMOGRAPH
COMPRISING SAID SENSOR
ARRANGEMENT AND
CORRESPONDING
PRODUCTION METHOD

Examiner: Not yet assigned

Art Unit: N/A

Attorney Docket No: 10808/217

INFORMATION DISCLOSURE STATEMENT

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and §§1.97-1.98, and more particularly in accordance with 37 C.F.R. §1.97(b), Applicant hereby cites the following reference(s):

No.	Date of Publication	Patentee/Applicant/Assignee
4,982,096	January 1, 1991	Fujii et al.
4,940,901	July 10, 1990	Henry et al.
FOREIGN PATENT DOCUMENTS		
DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	COUNTRY
EP 1 291 676 A2	July 25, 2002	EPO
EP 0 275 446	December 7, 1987	EPO
DE 3009723	September 24, 1981	Germany
OTHER ART – NON PATENT LITERATURE DOCUMENTS		
J.S. Drewery, G. Cho, I. Fujieda, T. Jing, S.N. Kaplan, V. Perez-Mendez and D. Wildermuth, <i>Amorphous Silicon Pixel Arrays</i> , Nuclear Instruments and Method in Physics Research A310, pgs. 165-170, 1991.		
Copy of International Examination Report from corresponding PCT application number PCT/DE2003/002675.		

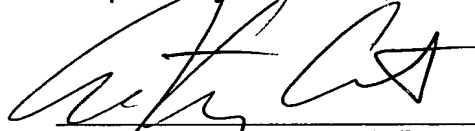
Applicant is enclosing Form PTO-1449 (one sheet), along with a copy of each listed reference for which a copy is required under 37 C.F.R. §1.98(a)(2). As each of the listed references is in English, no further commentary is believed to be necessary, 37 C.F.R §1.98(a)(3). Applicant respectfully requests the Examiner's

consideration of the above reference(s) and entry thereof into the record of this application.

By submitting this Statement, Applicant is attempting to fully comply with the duty of candor and good faith mandated by 37 C.F.R. §1.56. As such, this Statement is not intended to constitute an admission that any of the enclosed references, or other information referred to therein, constitutes "prior art" or is otherwise "material to patentability," as that phrase is defined in 37 C.F.R. §1.56(a).

Applicant has calculated no fee to be due in connection with the filing of this Statement. However, the Director is authorized to charge any fee deficiency associated with the filing of this Statement to a deposit account, as authorized in the Transmittal accompanying this Statement.

Respectfully submitted,



Anthony P. Curtis, Ph.D.
(Reg. No. 46,193)

2/24/05
Date

10/525649

DT15 Rec'd PCT/PTO 24 FEB 2005

FORM PTO-1449	SERIAL NO. Not yet assigned	CASE NO. 10808/217
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE Herewith	GROUP ART UNIT Not yet assigned
(use several sheets if necessary)		APPLICANT(S): Werner Kuhlmann et al.

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
	A1	4,982,096	January 1, 1991	Fujii et al.		
	A2	4,940,901	July 10, 1990	Henry et al.		

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO
	A3	EP 1 291 676 A2	July 25, 2002	EPO		
	A4	EP 0 275 446	December 7, 1987	EPO		
	A5	DE 3009723	September 24, 1981	Germany		

OTHER ART - NON PATENT LITERATURE DOCUMENTS

EXAMINER INITIAL		(Include name of author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.
	A6	J.S. Drewery, G. Cho, I. Fujieda, T. Jing, S.N. Kaplan, V. Perez-Mendez and D. Wildermuth, <i>Amorphous Silicon Pixel Arrays</i> , Nuclear Instruments and Method in Physics Research A310, pgs. 165-170, 1991
	A7	Copy of International Examination Report from corresponding PCT application number PCT/DE2003/002675.

EXAMINER	DATE CONSIDERED
----------	-----------------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.